# Threadmill: A Post-Silicon Exerciser for Multi-Threaded Processors

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## Outline

#### Motivation

Overview of Threadmill

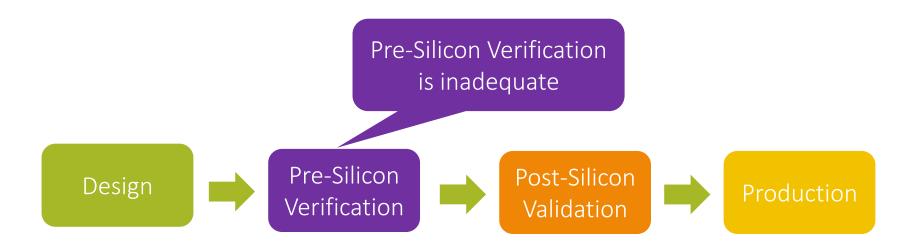
Key Techniques of Threadmill

Conclusion

Questions

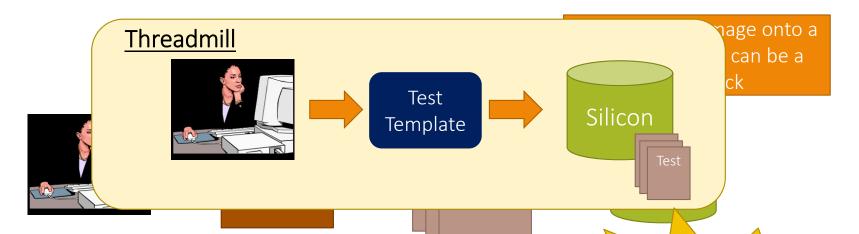
Debate!

### Motivation – Why Post Silicon?



 Post-Silicon validation is becoming the next-level vehicle for functional verification

#### Problems of Post-Silicon Validation



- Loading tests externally have high communication and memory overhead
- Existing on-platform test generators are to
- Developing full OS system takes time

Simple on-platform test generator

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#### Overview of Threadmill

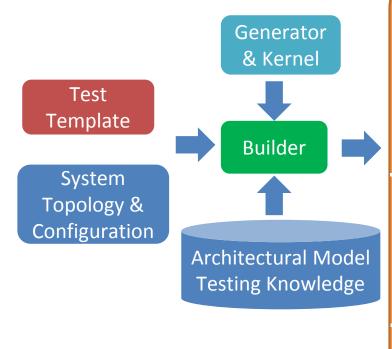
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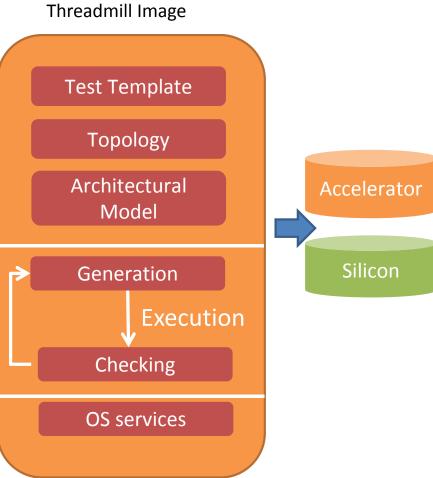
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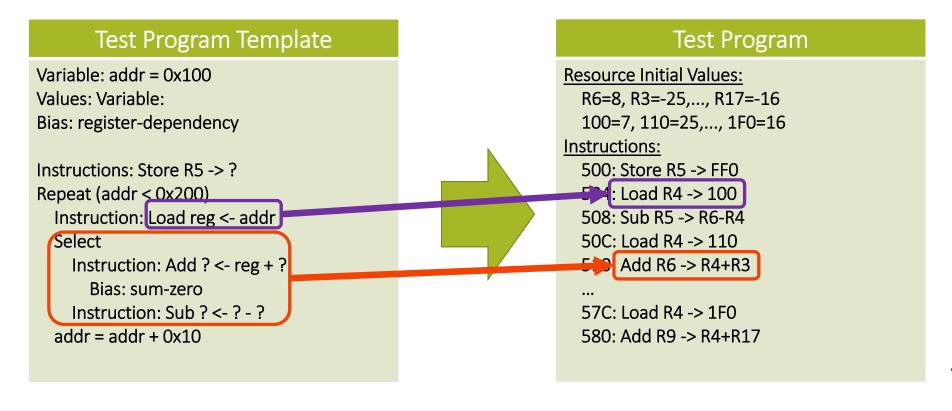
Debate!

#### Threadmill Architecture

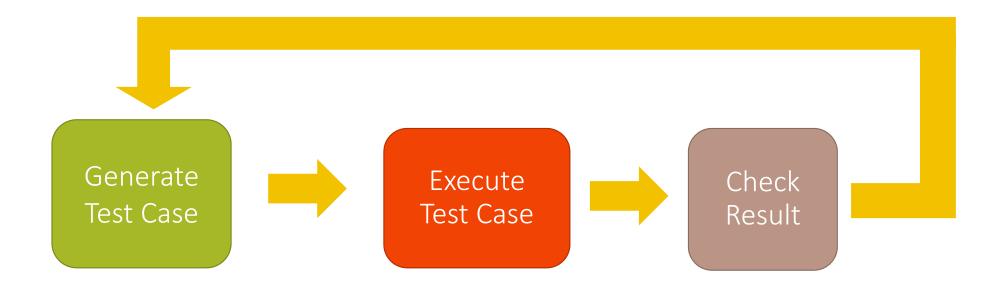




## Test-Template Language



## **Execution Process**



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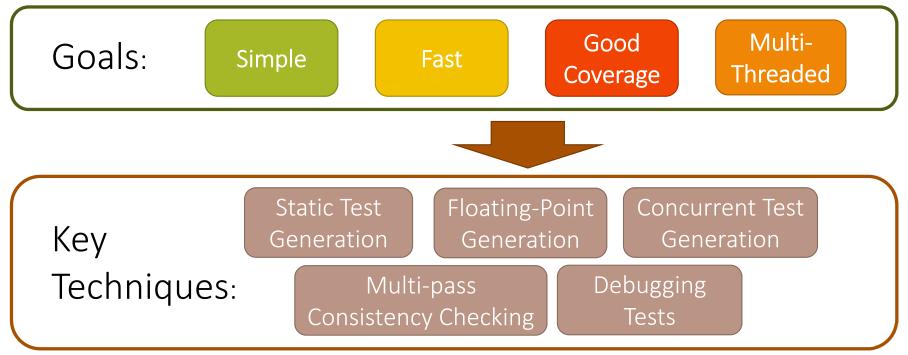
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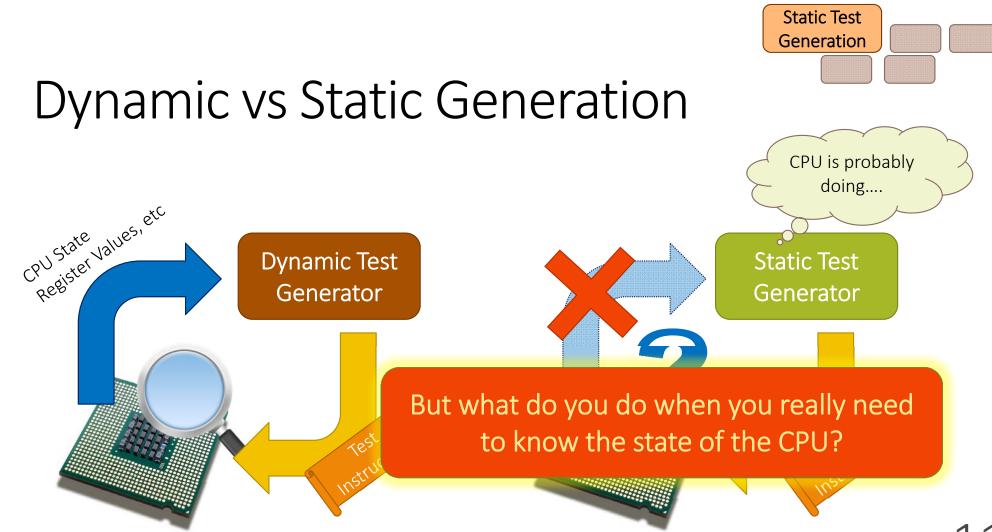
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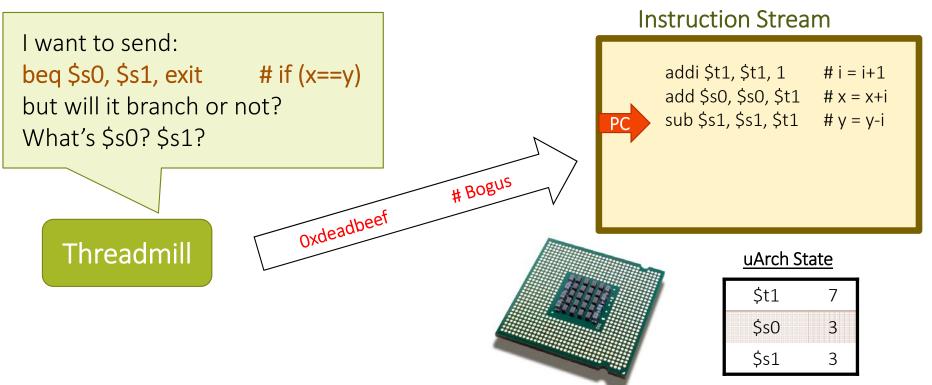
# Threadmill Design





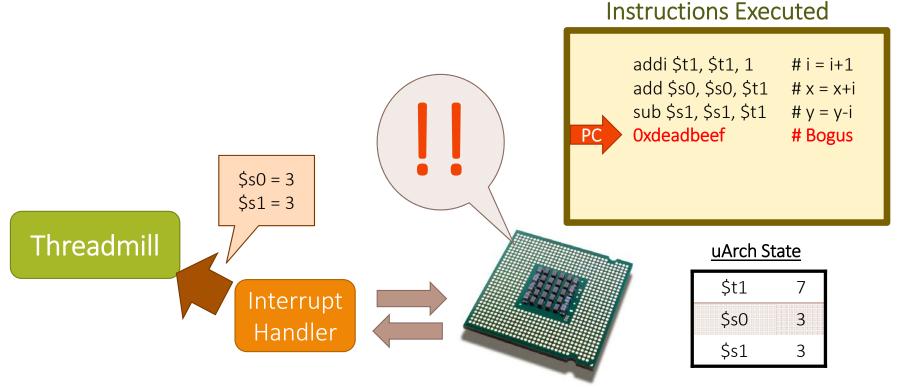
#### Static Test Generation

## Observing Machine State



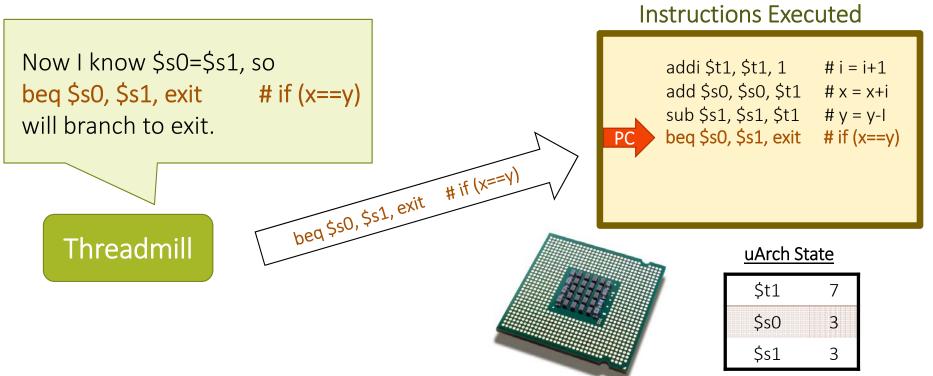
#### Static Test Generation

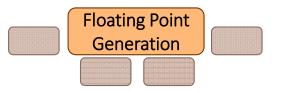
## Observing Machine State



#### Static Test Generation

## Observing Machine State





## Floating-Point Instructions

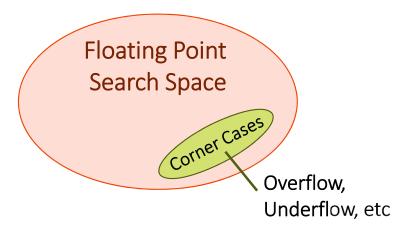
How to choose argument values?

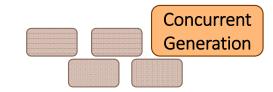
random inefficient

FPgen: Generate table of interesting test cases "off-line"

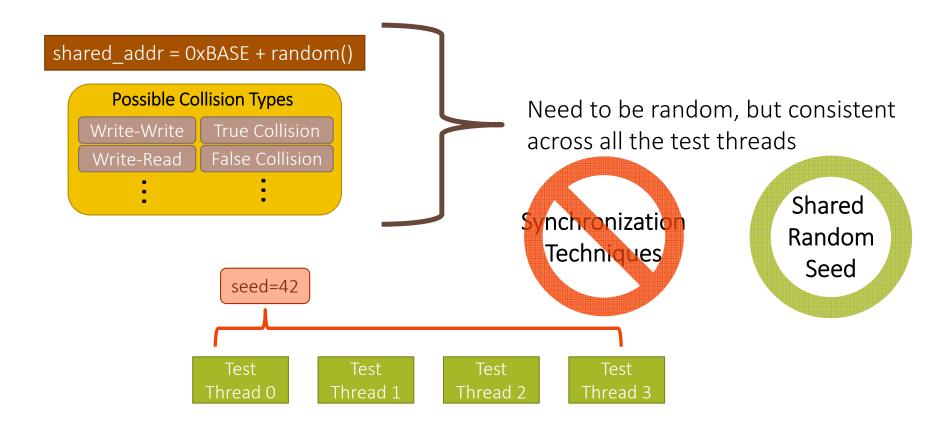


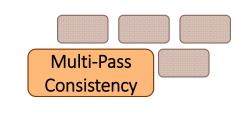






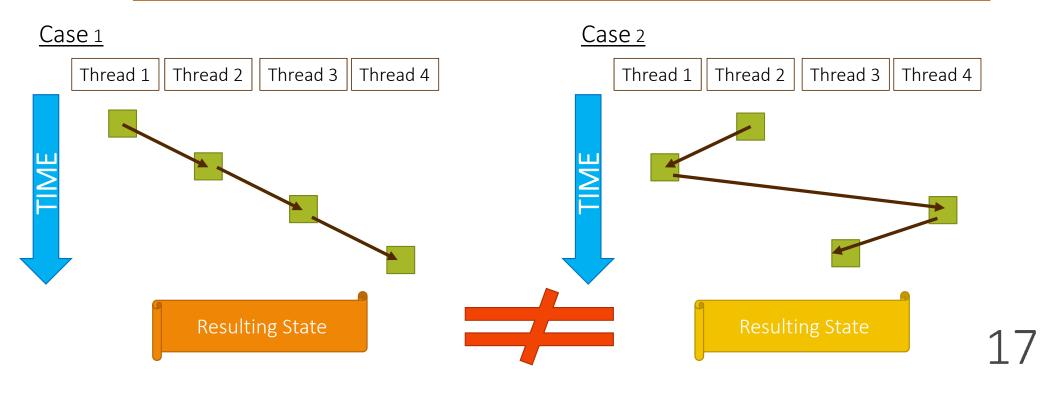
### Concurrent Test Generation

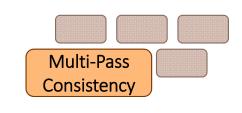




## Multi-Pass Consistency Checking

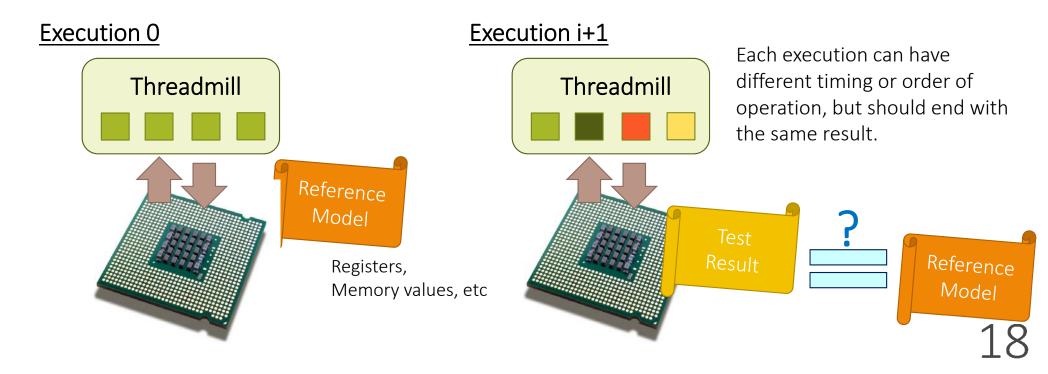
Main Focus: Detecting Bugs in Multi-Threaded Consistency





## Multi-Pass Consistency Checking

Main Focus: Detecting Bugs in Multi-Threaded Consistency



# Debugging Tests

## Debugging Tests

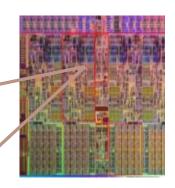
- Restart the failed exerciser image a few test-cases before the failure
- Take the test-template that causes the bug and run it on a pre-silicon test generation











#### Conclusion

#### **Strengths**

- ✓ Fast and Light-weight.
- ✓ Automatic testing and checking of multi-threaded execution.

#### Weakness

- Doesn't check datapath or permanent bugs.
- ☐ Little evaluation of performance or coverage of the platform (paper).

# Questions?

### Debate

Threadmill's failure detection mechanism only checks for bugs in multi-threaded interactions, and do not check bugs in the datapath. Is this adequate?

Instead of generating tests on-chip, isn't it better to simply load pre-generated tests?

